QUALIFICATION PLAN SUMMARY

PCN #: BLAS-22UEXX178

Date:
March 06, 2026

Qualification of OSE as a new final test site for ATSENSE201HA-AU, ATSENSE101A-SU, ATSENSE101A-SUR, ATSENSE201A-AU, ATSENSE201A-AUR, ATSENSE201HA-AUR, ATSENSE301A-AN, ATSENSE301A-ANR, ATSENSE301A-AU, ATSENSE301A-AUR, ATSENSE301HA-AU and ATSENSE301HA-AUR catalog part numbers (CPN) available in 20L SOIC (.300in) and 32L TQFP (7x7x1mm) package.

Purpose: Qualification of OSE as a new final test site for ATSENSE201HA-AU, ATSENSE101A-SU, ATSENSE101A-SUR, ATSENSE201A-AU, ATSENSE201A-AUR, ATSENSE201HA-AUR, ATSENSE301A-AN, ATSENSE301A-ANR, ATSENSE301A-AU, ATSENSE301A-AUR, ATSENSE301HA-AU and ATSENSE301HA-AUR catalog part numbers (CPN) available in 20L SOIC (.300in) and 32L TQFP (7x7x1mm) package.

CCB No.: 8171

Test Name	Test Conditions	Sample Size	Qty of Lots	Fail/Accept Criteria
Bin and Yield Comparison	Test ~3,000 tested devices from original test site and re-test at destination site to original flows and keep the good devices and rejects in separate bins Compare results between old and new test site. Results should be within 0.1%	3000	1	≤0.1%
Parametric / Characterization Comparison	Re-characterize the same 33 good devices at the destination test site using the destination site tester, hardware, test program for the same DC and measurable functional tests on each ATE Tester. The results must be within ± 10% of measured values from original test site.	33	1	≤10.0%
Correlation Lot Report	Characterize 33 good devices at the original test site with DC items and measurable functional test items specified from product datasheet and send same devices to the destination final test site	33	1	≤0.1%